

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/713,047	YUEH, WEN HSIANG	
	Examiner	Art Unit	Page 1 of 1
	Duc M. Nguyen	2618	

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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